

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20130322000 Qualification of CAR as an Additional Assembly Site for Select Devices in the SSOP (DB) Package Change Notification / Sample Request

Date: 3/25/2013

To: Newark/Farnell PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www_admin_team@list.ti.com).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

20130322000 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
DAC7631EB	null
DAC7613E	null
DAC7631E	null
DAC7731E	null
DAC7621E	null
DAC7731EC	null
DAC7614EB	null

Technical details of this Product Change follow on the next page(s).

PCN Number: 20130322000 **PCN Date:** 03/25/2013 Qualification of CAR as an Additional Assembly Site for Select Devices in the Title: SSOP (DB) Package PCN Manager **Customer Conact: Phone:** +1(214)480-6037 **Dept:** Quality Services **Estimated Sample** Date provided at sample **Proposed 1st Ship Date:** 06/25/2013 **Availability:** request **Change Type: Assembly Materials Assembly Site Assembly Process** Design **Electrical Specification** Mechanical Specification Packing/Shipping/Labeling **Test Site Test Process** Wafer Bump Material Wafer Bump Process Wafer Bump Site Wafer Fab Site Wafer Fab Materials Wafer Fab Process **PCN Details Description of Change:** Qualification of CAR as an Additional Assembly Site for Select Devices in the SSOP (DB) Package which are currently assembled at CRS. **Reason for Change:** Continuity of supply. Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): None. Changes to product identification resulting from this PCN: Sample Product Shipping Label (not actual product label) Assembly Site **CRS** Assembly Site Origin (22L) ASO: CRS CAR Assembly Site Origin (22L) ASO: CAR **W** TEXAS (1P) SN74LS07NSR INSTRUMENTS MADE IN: Malaysia (a) 2000 (P) 0336 2Q: (31T)LOT: 3959047MLA MSL 2 /260C/1 YEAR SEAL DT 4W) TKY(1T) 7523483\$I2 MSL 1 /235C/UNLIM 03/29/04 (P) OPT: (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS (2P) REV: ITEM: (L)T0:1750

Product Affected: DAC7613E DAC7615E DAC7617E DAC7631E DAC7615EB DAC7613EB DAC7617EB DAC7631EB DAC7613EBG4 DAC7615EBG4 DAC7617EBG4 DAC7631EBG4 DAC7613EG4 DAC7615EG4 DAC7617EG4 DAC7631EG4 DAC7614E DAC7616E DAC7621E DAC7731E DAC7614EB DAC7616EB DAC7621EB DAC7731EC DAC7614EBG4 DAC7616EBG4 DAC7621EBG4 DAC7731ECG4 DAC7614EG4 DAC7616EG4 DAC7621EG4 DAC7731EG4

DB Qualification Data: Approved 3/21/2013

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.						
Qual Device 1: ADS1213E (MSL 2-260C)						
Package Construction Details						
Assembly Site:	CAR Mold Compound:			438360		
# Pins-Designator, Family:	28-DB, SSOP		Mount Compound:	434165		
Leadframe (Finish, Base):	NiPdAu, Cu		Bond Wire:	1.3 Mil Dia., AU		
Qualification: Plan Test Results						
Reliability Test	Conditions			Sample Size Pass/Fail		
**Unbiased HAST		130C/85%RI	H/33.3 psia (96 Hrs)	77/0		
**T/C -65C/150C		-65C/+150C	(500 Cyc)	77/0		
Manufacturability		(Assembly S	ite)	Pass		
Moisture Sensitivity, L2	85C/60%RH/168 Hrs		12/0			
Notes: ** Preconditioning sequence Level 2-260C						
Qual Device 2: ADS7871IDB (MSL 2-260C)						
Package Construction Details						
Assembly Site:	CAR		Mold Compound:	438358		
# Pins-Designator, Family:	28-DB, SSOP		Mount Compound:	434165		
Leadframe (Finish, Base):	NiPdAu, (Cu Bond Wire		1.3 Mil Dia., AU		
Qualification:	1 🛚 Te	est Results				
Reliability Test		Conditions		Sample Size/Fail		
**Unbiased HAST 13		130C/85%RH/33.3 psia (96 Hrs)		77/0		
**T/C -65C/150C -65C/+150		-65C/+150C	(500 Cyc)	77/0		
Manufacturability (Assembly Si		ite)	Pass			
Moisture Sensitivity, L2 85C/60%F		0FC/C00/ DII	/160 Ura	12/0		
Notes: ** Preconditioning sequence Level 2-260C						
Notes: ** Preconditioning	sequenc			12/0		
Notes: ** Preconditioning		e Level 2-260		,		
Notes: ** Preconditioning	Qual De	e Level 2-260 vice 3: ADS	С	,		
Notes: ** Preconditioning Assembly Site:	Qual De	e Level 2-260 vice 3: ADS	C S825E (MSL 2-260C)	,		
	Qual De Pa	e Level 2-260 vice 3 : ADS	C S825E (MSL 2-260C) ruction Details			

Qualification:	ı 🛛 Te	est Results					
Reliability Test	-			Sample Size/Fail			
Solderability Pb-Free/So		Pb-Free/Solo	der	22/0			
**Unbiased HAST			H/33.3 psia (96 Hrs)	77/0			
		-65C/+150C	(500 Cyc)	77/0			
Manufacturability		(Assembly S	ite)	Pass			
, , ,		Mechanical o	drawing	5/0			
Moisture Sensitivity, L2 85C/60%RH			12/0				
Notes: ** Preconditioning							
Qı			820IBDB (MSL 2-260)C)			
	1	ickage Const	ruction Details				
Assembly Site:	CAR		Mold Compound:	438518			
# Pins-Designator, Family:		SSOP	Mount Compound:	434165			
Leadframe (Finish, Base):			Bond Wire:	1.3 Mil Dia., AU			
Qualification: Plan Test Results							
Reliability Test		Conditions	Conditions		Sample Size/Fail		
rendbiney rese			Conditions		Lot 2	Lot 3	
Manufacturability			i	Pass	Pass	Pass	
		ge, Pb-Free/Solder	22/0	22/0	-		
		H/33.3 psia (96 Hrs)	77/0	77/0	77/0		
**T/C -65C/150C -65C/+150C			77/0	77/0	77/0		
Physical Dimensions Mechanical			5/0 12/0	-	-		
,,			35C/60%RH/168 Hrs		12/0	-	
Notes: ** Preconditioning sequence Level 2-260C							
Qual Device 5: PGA2505IDB (MSL 2-260C)							
Package Construction Details							
Assembly Site:	CAR		Mold Compound:	438360			
# Pins-Designator, Family:	24-DB, SSOP		Mount Compound:	434165			
Leadframe (Finish, Base):	NiPdAu, Cu		Bond Wire:	1.3 Mil Dia., AU			
Qualification: Plan Test Results							
Reliability Test Conditions			Sample Size/Fail				
**Unbiased HAST	·		H/33.3 psia (96 Hrs)	77/0			
**T/C -65C/150C -65C/+150C		1	77/0				
Manufacturability (Assembly Si		i	Pass				
Physical Dimensions Mechanical of Mechanical			5/0				
Moisture Sensitivity, L2 85C/60%RH/168 Hrs 12/0							
Notes: ** Preconditioning sequence Level 2-260C							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com